

Contents

Part I Nano-imaging by Transmission Electron Microscopy

1	Seeing Nanometer-Sized World	3
1.1	What is the Nanoworld? How Much is Its Size?	3
1.2	Necessity of Study for Nanoscience and Nanoimaging.	6
1.3	Basic Modes for Imaging	8
1.4	Why are Electrons Necessary for Nanoimaging?	10
1.5	Three Methods for Seeing Isolated Single Atoms.	12
1.6	Summary	15
	Problems.	15
	References.	15
2	Structure and Imaging of a Transmission Electron Microscope (TEM)	17
2.1	Structure of a Transmission Electron Microscope.	17
2.2	Basic Action of a Magnetic Round Lens	22
2.3	Mathematics for Describing Lens Actions	24
2.4	Summary	27
	Problems.	27
	References.	28
3	Basic Theories of TEM Imaging	29
3.1	How to Describe a Wave in Three-Dimensional Space?.	29
3.2	Why Does an Electron Microscope Visualize an Objects in Analogy with a Light Microscope?.	33
3.3	Why Can a Single Atom be Observed by an Electron Microscope?.	35
3.4	Images and Diffraction Patterns	38
3.5	Summary	41
	Problems.	42
	References.	42

4	Resolution and Image Contrast of a Transmission Electron Microscope (TEM)	43
4.1	Simple Estimation of Point-to-Point Resolution of a TEM . . .	43
4.2	Limitation by Chromatic Aberration of an Objective Lens . . .	48
4.3	Effects of Other Aberrations on Image Resolution in TEM . . .	49
4.4	Image Contrast of a Transmission Electron Microscope Image	50
4.5	Bright-Field Images	52
4.6	Dark-Field Images	55
4.7	Summary	56
	Problems	56
	References	57
5	What is High-Resolution Transmission Electron Microscopy?	59
5.1	How Can We Observe a Single Atom by TEM? – Magic of Phase Contrast –	59
5.2	A Second-Order Theory for Single-Atom Imaging	64
5.3	Phase Contrast of Atomic Clusters	66
5.4	Imaging of Amorphous Films and Thon's Experiment	68
5.5	Diffraction Contrast of Microcrystallites	69
5.6	Where Does an Objective Lens Focus in Thin Specimens? . . .	70
5.7	Key Concepts of High-Resolution Imaging	71
5.8	Summary	71
	Problems	72
	References	72
6	Lattice Images and Structure Images	73
6.1	Interference of Two Waves in Three-Dimension	73
6.2	Lattice Images by Two-Wave Interference from a Crystal	75
6.3	Three-Wave Interference and Fourier Images	78
6.4	MultiWave Lattice Images	79
6.5	What is a Structure Image of Thicker Crystals	82
6.6	Other Lattice Images	84
6.7	Summary	85
	Problems	85
	References	85
7	Imaging Theory of High-Resolution TEM and Image Simulation	87
7.1	Linear Imaging Theory of TEM for Single-Crystal Specimens	87
7.1.1	Description of Phase Modulation by a Thin Specimen	87
7.1.2	Exit Wave Field for a Thicker Crystal	89
7.1.3	Lens Transfer Function	89

7.1.4	Phase Contrast Caused by Aberrations of an Objective Lens	90
7.1.5	Contrast Transfer Function Described in Reciprocal Space.	91
7.1.6	Effects of a Slight Convergence of Incident Electron Waves and Fluctuation of Accelerating Voltage	93
7.1.7	Imaging Theory of Weak-Amplitude Objects	94
7.1.8	Effects of Inelastic Scattering on HRTEM Images	96
7.2	Image Simulation of High-Resolution TEM Images	97
7.2.1	Necessity of the Simulation	97
7.2.2	Principle and Method of Simulation	98
7.2.3	What is the Supercell Method in Image Simulation	100
7.3	Coherence Problems in TEM Imaging	102
7.3.1	Imaging Theory of TEM and the Related Coherence of Incident Waves	102
7.3.2	Contrast of Interference Fringes and the Definition of Coherence	104
7.3.3	Temporal Coherence and Spatial Coherence of Waves	105
7.4	Summary	109
	Problems	109
	References	109
8	Advanced Transmission Electron Microscopy	111
8.1	Energy-Filtered Transmission Electron Microscopy (EFTEM)	111
8.1.1	Basic Theory of Electron Energy Loss Spectroscopy (EELS).	111
8.1.2	EELS in Image and Diffraction Modes	113
8.1.3	Practical Energy-Filtered TEM Instruments	115
8.1.4	What is Elemental Mapping Image?	116
8.1.5	Spatial Resolution of Energy-Filtered TEM Images	117
8.2	Electron Holography	118
8.2.1	What is Holography?	118
8.2.2	Instruments for Electron Holography	120
8.2.3	What Can We Do Using Electron Holography?	122
8.3	Electron Tomography – 3D Visualization of Nanoworld –	126
8.3.1	Principle of 3D Tomography	126
8.3.2	Application of the Principle to TEM	129

8.3.3	Actual Instruments for Electron Tomography	130
8.3.4	Present Issues in Electron Tomography	130
8.4	Aberration-Corrected Transmission Electron Microscopy	132
8.4.1	Overview of Spherical Aberration Correction in TEM	132
8.4.2	Aberrations of Magnetic Round Lens	134
8.4.3	Basic Principle of Spherical Aberration Correction	134
8.4.4	Actual Aberration Corrector for TEM	138
8.4.5	Benefits of Aberration-Corrected TEM	140
8.4.6	Correction of Chromatic Aberration in TEM	143
8.5	Summary	144
	Problems	144
	References	144

Part II Nano-imaging by Scanning Transmission Electron Microscopy

9	What is Scanning Transmission Electron Microscopy (STEM)?	149
9.1	Characteristics of STEM	149
9.1.1	Comparison between TEM, SEM, and STEM	149
9.1.2	Application Possibilities of STEM	152
9.2	Basics for nm-Sized Electron Probe (Geometrical Optical Approach)	152
9.3	Principle of Image Formation in STEM	155
9.4	Actual Instrument of STEM	157
9.5	Summary	158
	Problems	158
	References	158
10	Imaging of Scanning Transmission Electron Microscopy (STEM)	161
10.1	Reciprocal Theorem between STEM and TEM	161
10.2	Imaging Modes in STEM	163
10.3	Summary	165
	Problems	166
	References	166
11	Image Contrast and Its Formation Mechanism in STEM	167
11.1	Bright-Field Image Contrast and Lattice Images with Phase Contrast	168
11.2	Crewe's Z-Contrast of a Single Atom	169
11.3	Pennycook's Z^{2-x} -Contrast in Annular Dark-Field (ADF) STEM	171

11.4	Depth-Sectioning for ADF-STEM Images	175
11.5	Annular Bright-Field (ABF) STEM – Revival of Bright-Field Imaging in STEM –	177
11.6	Elemental Mapping Imaging by EELS and EDX in STEM . . .	178
11.7	Secondary Electron Imaging in STEM	182
11.8	Scanning Confocal Electron Microscopy (SCEM)	182
11.9	High-Voltage STEM	183
11.10	Electron Tomography by STEM	184
11.10.1	Image Contrast of Amorphous Specimens	185
11.10.2	STEM Tomography of Crystalline Specimens	186
11.10.3	3D Images Using EELS Signals and EDX Ones	186
11.10.4	Topography Versus Tomography for 3D Representation	187
11.11	Nanodiffraction in STEM	187
11.12	Summary	189
	Problems	189
	References	189
12	Imaging Theory for STEM	191
12.1	Basic Concept of Imaging Theory for STEM	191
12.2	Cowley–Moodie’s Multislice Method	192
12.3	Bethe’s Bloch Wave Method	199
12.4	Summary	201
	Problems	202
	References	202
13	Future Prospects and Possibility of TEM and STEM	203
13.1	Image Resolution	203
13.2	Effects of Chromatic Aberration	204
13.3	Development of Electron Energy Loss Spectroscopy (EELS)	205
13.4	Simulation for Quantitative Estimation for TEM and STEM Images	205
13.5	Development of Elemental Analysis Using EDX	205
13.6	Other Signal Detection for STEM Imaging	206
13.7	Electron Tomography in TEM and STEM	206
13.7.1	Ordinary Electron Tomography	206
13.7.2	HRTEM Method for the Extraction of 3D Information of Small Particles	207
13.7.3	Depth-Sectioning Method in ADF-STEM	207
13.7.4	Confocal Imaging Mode in STEM	208
13.8	Toward Lower Voltage TEM and STEM	208
13.9	In Situ Observation and High-Resolution Observation in Gas and Liquid Atmospheres	209

13.10	Pulsed Electron Beam for Time-Resolved Observation and Its New Possibility	209
13.11	Use of Spin-Polarized Electron Beams and Vortex Electron Beams	210
	References	211
14	Concluding Remarks	213
	References	215
 Part III Appendix: Basics for Understanding TEM and STEM Imaging		
15	Introduction to Fourier Transforms for TEM and STEM	219
15.1	Fourier Series	219
15.2	Fourier Integral (Fourier Transform)	220
15.3	Two-Dimensional and Three-Dimensional Fourier Transforms	221
15.4	Properties of Fourier Transforms	221
15.5	Fourier Transform of a Product of Two Functions	222
15.6	Parseval's Relation	223
15.7	Relationship between Various Fourier Transforms and Phenomena in Optics and Diffraction	224
15.8	Sign Convention for Fourier Transforms	226
	References	226
16	Imaging by Using a Convex Lens as a Phase Shifter	227
16.1	Propagation of Electron Waves	227
16.2	Action of a Convex Lens	230
	References	233
17	Contrast Transfer Function of a Transmission Electron Microscope	235
	References	242
18	Complex-Valued Expression of Aberrations of a Round Lens	243
	References	245
19	Cowley's Theory for TEM and STEM Imaging	247
19.1	Transmission Electron Microscope (TEM) Images	247
19.2	Scanning Transmission Electron Microscope (STEM) Images	249
	References	251
20	Introduction to the Imaging Theory for TEM Including Nonlinear Terms	253
20.1	What is Mutual Intensity?	253
20.2	Interaction with Specimens and Image Intensity	256

20.3	Nonlinear Imaging Theory for High-Resolution TEM.	258
	References.	259
21	What are Image Processing Methods?	261
	References.	263
22	Elemental Analysis by Electron Microscopes	265
	References.	266
23	Electron Beam Damage to Specimens	267
23.1	Damage to Non-Biological Specimens	267
23.2	Damage to Organic and Biological Specimens	268
23.3	Future Prospects	271
	References.	271
24	Scattering of Electrons by an Atom	273
	References.	278
25	Electron Diffraction and Convergent Beam Electron Diffraction (CBED)	279
	References.	286
26	Bethe's Method for Dynamical Electron Diffraction	287
	References.	291
27	Column Approximation and Howie-Whelan's Method for Dynamical Electron Diffraction	293
27.1	Column Approximation	293
27.2	Dynamical Diffraction Theory Developed by Howie and Whelan	295
	References.	296
28	Van Dyck's Method for Dynamical Electron Diffraction and Imaging	297
	References.	300
29	Eikonal Theory for Scattering of Electrons by a Potential	301
	References.	303
30	Debye-Waller Factor and Thermal Diffuse Scattering (TDS)	305
	References.	307
31	Relativistic Effects to Diffraction and Imaging by a Transmission Electron Microscope	309
	References.	312
	Author Index	313
	Subject Index	317

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